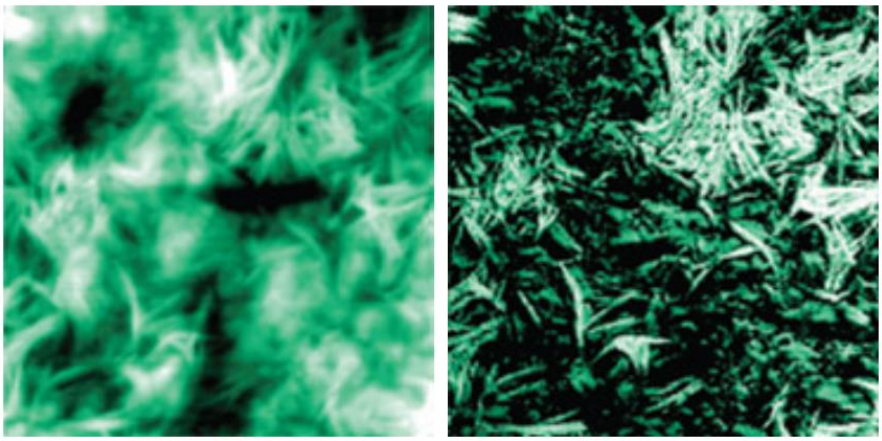
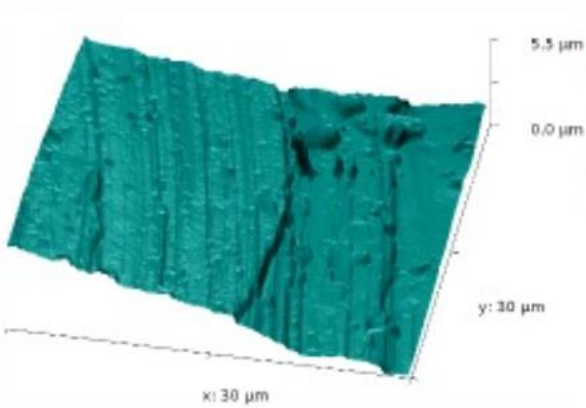
Galería SA AFM

Polymer sample. The image at left is a topography image, and the image at right is the phase image, measuring the relative hardness of the polymer sample.



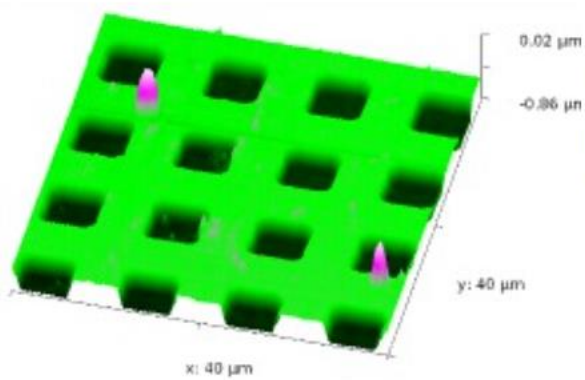
Surface Texture



Polished Surface - 30 x 30 x 5 µm

Surface texture on polished and machined surfaces is readily measured with the SA AFM. With the SA's flexible stage design, fixtures for holding almost any sample shape can be created. Once measured, the AFM images can be analyzed and standard surface texture parameters such as Ra are readily calculated.

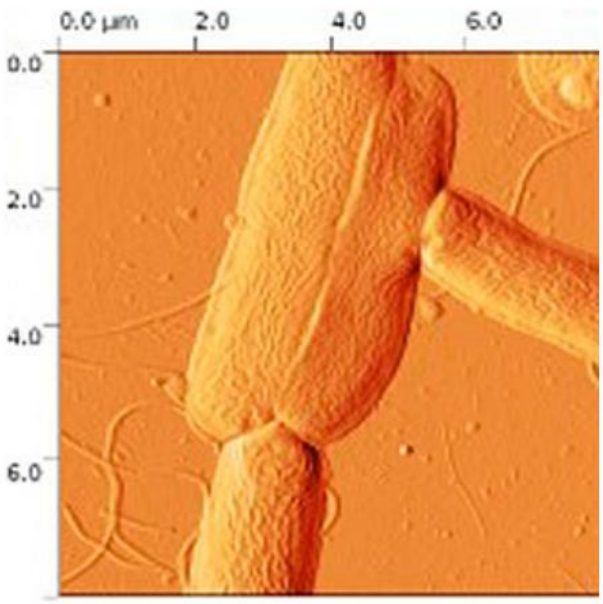
Dimensional



Calibration reference - 40 x 40 x 1 µm

Atomic force microscopes are capable of accurately measuring the dimensions of semiconductor and other micro-fabricated devices. Because the SA AFM accommodates commercially available AFM probes, specialized probes for metrology measurements can be used.

Visualization



Cells - 8 x 8 µm

One of the most powerful capabilities of the SA AFM is the capability to visualize surface structure. Although not easily quantified, the surface texture of this cell structure is readily visualized.

Features that may be readily visualized with the SA AFM range in size from a few nm to a few µm.

Para más información: https://www.afmworkshop.com/afm-products/atomic-force-microscopes/sa-afm